Hybrid 8j85 Traveler

November 15, 1999

1 Connectivity

Repairs on shorts:

Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 8J85 has die: 090-037 090-038 090-040 090-041 098-047 098-048 098-052 025-003

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 8j85 classification info. Created 12:43:02 11/15/99

Hybrid 8j85 quality: fair
Chip classification: good fair good good good good good good
Bad channels (chip-channel): 1-6 1-33
Bad cells: none
Random bad capacitors (chip-cell-channel): 1-10-6 1-12-6 1-12-7
   1-14-6 1-14-7 1-16-6 1-16-7 1-17-6 1-25-5 1-25-6 1-25-7
   1-26-5 1-26-6 1-27-33 1-38-6 1-5-6 1-5-7 1-9-6 1-9-7
Channels at pedestal needed for DCMS: 34.6 34.6 36.6 35.7 33.7 34.6 35.3 34.6
```

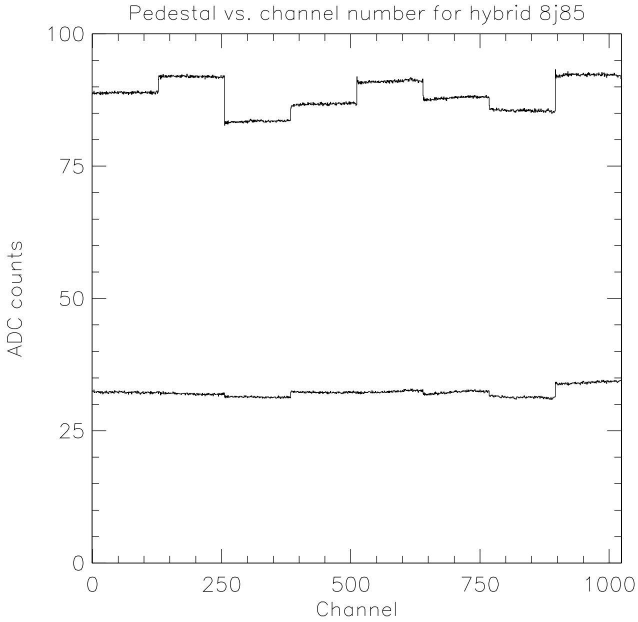
4 Comments

No comments.

5 Pedestal

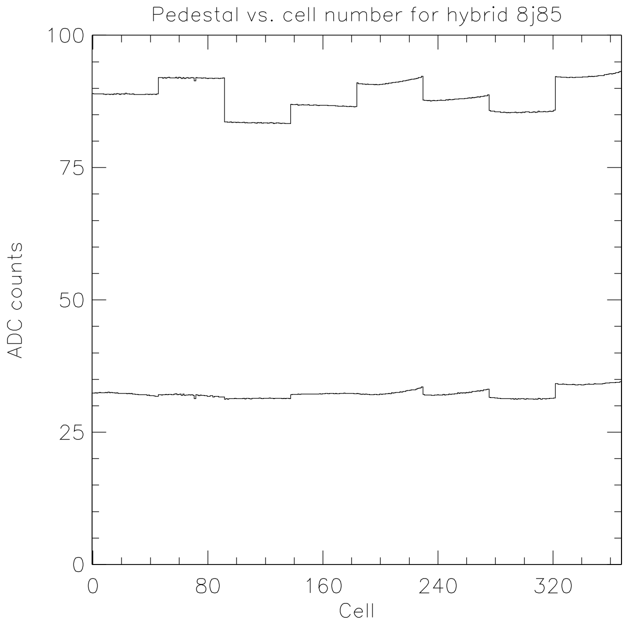
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

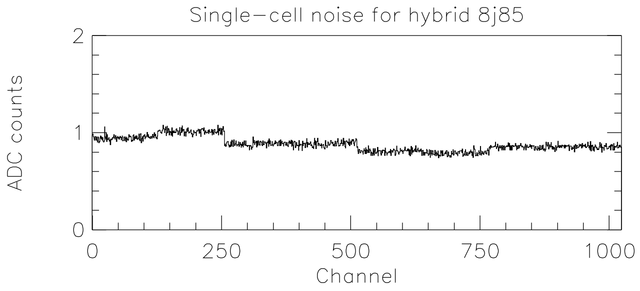
Pedestal vs. Pipeline Cell ID

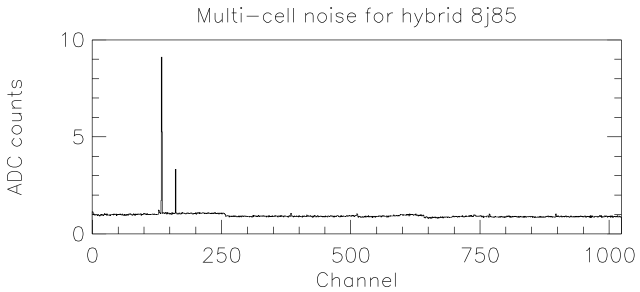


6 Noise

The following plots show the single-cell and multi-cell RMS noise:

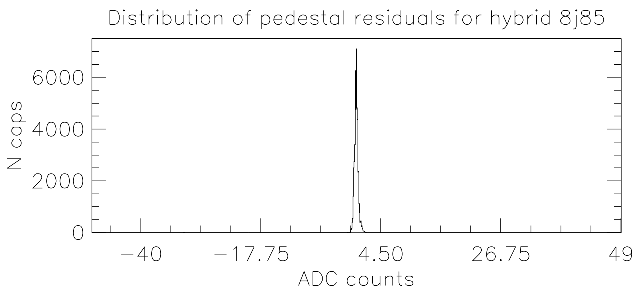
RMS Noise

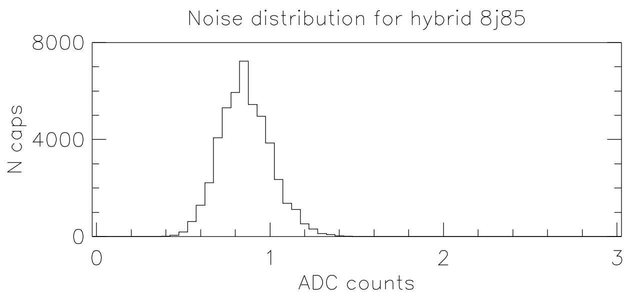




The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise





7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in